

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,020	RAPCHAK	
Examiner	Art Unit	-
Anh V. La	2636	

SEARCHED					
Class	Subclass	Date	Examiner		
340.	691.1	5/02/00	AL		
	691.6		1		
	573.1				
	309.15				
	825,19				
	666				
368	10				
368 70 °	2)		
			•		
			<u> </u>		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
		· ·			
·					
`					